

PCN Number:	20230327000.1		PCN Date:	March 28, 2023								
Title:	Add Cu as Alternative Wire Base Metal for Selected Device(s)											
Customer Contact:	PCN Manager	Dept:	Quality Services									
Proposed 1st Ship Date:	June 28, 2023	Sample requests accepted until:	Apr. 28, 2023*									
*Sample requests received after (Apr. 28, 2023) will not be supported.												
Change Type:												
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Material							
<input checked="" type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Process							
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Fab Site							
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Materials							
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Process							
PCN Details												
Description of Change:												
Texas Instruments is pleased to announce the qualification of new assembly material set to add Cu as an additional bond wire option for devices listed in "Product affected" section below. Devices will remain in current assembly facility and piece part changes as follows:												
<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th style="width: 20%;">Material</th> <th style="width: 40%;">Current</th> <th style="width: 40%;">Proposed</th> </tr> </thead> <tbody> <tr> <td>Wire type</td> <td>0.6mil, 0.8mil, 1.0mil, 1.3mil Au</td> <td>0.8mil, 1.0mil, 1.3mil Cu</td> </tr> </tbody> </table>					Material	Current	Proposed	Wire type	0.6mil, 0.8mil, 1.0mil, 1.3mil Au	0.8mil, 1.0mil, 1.3mil Cu		
Material	Current	Proposed										
Wire type	0.6mil, 0.8mil, 1.0mil, 1.3mil Au	0.8mil, 1.0mil, 1.3mil Cu										
Reason for Change:												
Continuity of supply. 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock												
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):												
None.												
Impact on Environmental Ratings												
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.												
<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th style="width: 25%;">RoHS</th> <th style="width: 25%;">REACH</th> <th style="width: 25%;">Green Status</th> <th style="width: 25%;">IEC 62474</th> </tr> </thead> <tbody> <tr> <td><input checked="" type="checkbox"/> No Change</td> </tr> </tbody> </table>					RoHS	REACH	Green Status	IEC 62474	<input checked="" type="checkbox"/> No Change			
RoHS	REACH	Green Status	IEC 62474									
<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change									
Changes to product identification resulting from this PCN:												
None.												
Product Affected:												

INA180A1IDBVR	OPA314AIDBVR	TLV707T18DBVR	TPS70912DBVT
INA180A1IDBVT	OPA314AIDBVT	TLV707T18DBVT	TPS709135DBVR
INA180A2IDBVR	OPA316IDBVR	TLV707T28DBVR	TPS709135DBVT
INA180A2IDBVT	OPA316IDBVT	TLV707T28DBVT	TPS70915DBVR
INA180A3IDBVR	OPA320AIDBVR	TLV707T30DBVR	TPS70915DBVT
INA180A3IDBVT	OPA320AIDBVT	TLV707T30DBVT	TPS70916DBVR
INA180A4IDBVR	OPA322AIDBVR	TLV707T33DBVR	TPS70916DBVT
INA180A4IDBVT	OPA322AIDBVT	TLV707T33DBVT	TPS70918DBVR
INA180B1IDBVR	OPA377AIDBVR	TLV71210DBVR	TPS70918DBVT
INA180B1IDBVT	OPA377AIDBVT	TLV71210DBVT	TPS70925DBVR
INA180B2IDBVR	SN1603068DBVR	TLV71211DBVR	TPS70925DBVT
INA180B2IDBVT	SN74AUC1G126DBVR	TLV71211DBVT	TPS70927DBVR
INA180B3IDBVR	SN74AUP1G02DBVR	TMP708AIDBVR	TPS70927DBVT
INA180B3IDBVT	SN74AUP1G02DBVT	TMP708AIDBVT	TPS70928DBVR
INA180B4IDBVR	SN74AUP1G06DBVT	TMP709AIDBVR	TPS70928DBVT
INA180B4IDBVT	SN74AUP1G07DBVT	TMP709AIDBVT	TPS70938DBVR
INA183A1IDBVR	SN74AUP1G126DBVR	TMP709SNDBVR	TPS70938DBVT
INA183A1IDBVT	SN74AUP1G126DBVT	TMP709SNDBVT	TPS70939DBVR
INA183A2IDBVR	SN74AUP1G17DBVT	TPS560200DBVR	TPS70939DBVT
INA183A2IDBVT	SN74AUP1G240DBVR	TPS560200DBVT	TPS70960DBVR
INA183A3IDBVR	SN74AUP1G240DBVT	TPS60400QDBVRSV	TPS70960DBVT
INA183A3IDBVT	SN74AUP1G34DBVT	TPS60402QDBVRDL	TPS709A30DBVR
INA195AIDBVR	SN74AUP1G80DBVR	TPS60403QDBVRHT	TPS709A30DBVT
INA195AIDBVR-S	SN74AUP1G80DBVT	TPS61097A-33DBVR	TPS709A33DBVR
INA195AIDBVT-S	TLV1701AIDBVR	TPS61097A-33DBVT	TPS709A33DBVT
INA198AIDBVR	TLV1701AIDBVT	TPS70612DBVR	TPS709B33DBVR
OPA170AIDBVR	TLV3201AIDBVR	TPS70612DBVT	TPS709B33DBVT
OPA170AIDBVT	TLV3201AIDBVT	TPS70615DBVR	TPS709B345DBVR
OPA171AIDBVR	TLV376IDBVR	TPS70615DBVT	TPS709B50DBVR
OPA171AIDBVT	TLV376IDBVT	TPS70618DBVR	TPS709B50DBVT
OPA180IDBVR	TLV6001RIDBVR	TPS70618DBVT	UCC27518DBVR
OPA180IDBVT	TLV6001RIDBVT	TPS70625DBVR	UCC27518DBVT
OPA188AIDBVR	TLV7011DBVR	TPS70625DBVT	UCC27519DBVR
OPA188AIDBVT	TLV7021DBVR	TPS70628DBVR	UCC27519DBVT
OPA192IDBVR	TLV70220PDBVR	TPS70628DBVT	UCC27533DBVR
OPA192IDBVT	TLV70220PDBVT	TPS70630DBVR	UCC27533DBVT
OPA197IDBVR	TLV70229DBVR	TPS70630DBVT	UCC27536DBVR
OPA197IDBVT	TLV70229DBVT	TPS70633DBVR	UCC27536DBVT
OPA313IDBVR	TLV7031DBVR	TPS70633DBVT	UCC27537DBVR
OPA313IDBVT	TLV7041DBVR	TPS70912DBVR	UCC27537DBVT

Qualification Report

Approve Date 20-Oct-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: <u>SN74LVC1G125DBVR</u>	QBS Reference: <u>TLV9061IDBVR</u>	QBS Reference: <u>TPS3840PH30DBVRQ1</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
AC	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0
HTOL	B1	Life Test	150C	300 Hours	-	3/231/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	3/228/0	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	3/228/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	3/66/0	1/15/0
PD	C4	Physical Dimensions	(per mechanical drawing)	-	1/5/0	3/15/0	3/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0

QBS: Qual By Similarity

Qual Device SN74LVC1G125DBVR is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 10-Nov-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: <u>TLV70333DBVR</u>	QBS Reference: <u>TLV9061IDBVR</u>	QBS Reference: <u>TPS3840PH30DBVRQ1</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
AC	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0
HTOL	B1	Life Test	150C	300 Hours	-	3/231/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	3/228/0	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	3/228/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	3/66/0	1/15/0
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	3/15/0	3/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0
FTY	E6	Final Test Yield	-	-	1/1/0	3/3/0	-

QBS: Qual By Similarity

Qual Device TLV70333DBVR is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 10-Nov-2021

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: <u>TLV9061IDBVR</u>	QBS Package Reference: <u>TLV9061IDBVR</u> (NiPdAu)	QBS Package Reference: <u>TPS76933DBVR</u> (PHI)
AC	Autoclave 121C	96 Hours	-	-	-
ED	Electrical Characterization, side by side	Per Datasheet Parameters	-	Pass	-
FLAM	Flammability (UL 94V-0)	--	-	-	3/15/0

Type	Test Name / Condition	Duration	Qual Device: <u>TLV9061IDBVR</u>	QBS Package Reference: <u>TLV9061IDBVR</u> (NiPdAu)	QBS Package Reference: <u>TPS76933DBVR</u> (PHI)
FLAM	Flammability (UL-1694)	-	-	3/15/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	-	-
HTOL	Life Test, 150C	300 Hours	3/231/0	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-	-
LI	Lead Fatigue	Leads	3/54/0	-	-
LI	Lead Pull	Leads	3/66/0	-	-
MISC	Salt Atmosphere	-	3/66/0	-	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	-	-
PD	Physical Dimensions	(per mechanical drawing)	3/15/0	-	-
PKG	Lead Finish Adhesion	Leads	3/54/0	-	-
SD	Solderability	Pb Free	3/66/0	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	-	-
UHA ST	Unbiased HAST 130C/85%RH	96 Hours	3/231/0	-	-
VM	Visual / Mechanical	(per mfg. Site specification)	3/984/0	-	-
WBP	Bond Pull	Wires	3/228/0	-	-
WBS	Ball Bond Shear	Wires	3/228/0	-	-

- QBS: Qual By Similarity

- Qual Device TLV9061IDBVR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

Qualification Report

Automotive New Product Qualification Summary
(As per AEC-Q100 and JEDEC Guidelines)
Approve Date 02-Jun-2022

Product Attributes

Attributes	Qual Device: TMS3840PH30DBVRQ1
Automotive Grade Level	Grade 1
Operating Temp Range	-40 to +125 C
Product Function	Power Management
Wafer Fab Supplier	RFAB
Die Revision	A
Assembly Site	CDAT
Package Type	SOT-23
Package Designator	DBV
Ball/Lead Count	5

- QBS: Qual By Similarity
- Qual Device 3840PH30DBVRQ1 is qualified at LEVEL1-260CG

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: 3840PH30DBVRQ1
Test Group A – Accelerated Environment Stress Tests							
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	Level 1-260C	No Fails
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST, 130C/85%RH	96 Hours	3/231/0
UHAST	A3	JEDEC JESD22-A102	3	77	Unbiased HAST 130C/85%RH	96 Hours	3/231/0
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle, -65/150C	500 Cycles	3/231/0
TC-WBP	A4	MIL-STD883 Method 2011	1	60	Post Temp Cycle Bond Pull	Wires	3/108/0
PTC	A5	JEDEC JESD22-A105	1	45	Power Temperature Cycle	1000 Cycles	N/A
HTSL	A6	JEDEC JESD22-A103	1	45	High Temp Storage Bake 150C	1000 Hours	3/231/0
Test Group B – Accelerated Lifetime Simulation Tests							
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test, 125C	1000 Hours	3/231/0
EDR	B3	AEC Q100-005	3	77	NVM Endurance, Data Retention, and Operational Life	-	N/A
Test Group C – Package Assembly Integrity Tests							
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear, Cpk>1.67	Wires	3/90/0
WBP	C2	MIL-STD883 Method 2011	1	30	Bond Pull, Cpk>1.67	Wires	3/90/0
SD	C3	JEDEC JESD22-B102	1	15	Surface Mount Solderability	Pb Free Solder	3/45/0
SD	C3	JEDEC JESD22-B102	1	15	Surface Mount Solderability	Pb Solder	3/45/0
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk>1.67	3/30/0
LI	C6	JEDEC JESD22-B105	1	50	Lead Fatigue	Leads	3/66/0
LI	C6	JEDEC JESD22-B105	1	50	Lead Pull to Destruction	Leads	3/66/0
Test Group D – Die Fabrication Reliability Tests							
EM	D1	JESD61	-	-	Electromigration	-	Completed Per Process Technology Requirements
TDDDB	D2	JESD35	-	-	Time Dependant Dielectric Breakdown	-	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Injection Carrier	-	Completed Per Process Technology Requirements
NBTI	D4	-	-	-	Negative Bias Temperature Instability	-	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	Completed Per Process Technology Requirements
Test Group E – Electrical Verification Tests							
ED	E5	AEC Q100-009	3	30	Auto Electrical Distributions	Cpk>1.67 Room, hot, and cold test	3/90/0

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40°C to +150°C

Grade 1 (or Q): -40°C to +125°C

Grade 2 (or T): -40°C to +105°C

Grade 3 (or I): -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
WW PCN Team	PCN_ww_admin_team@list.ti.com

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